

Hardware Security: Investigation of Fingerprinting (Advanced CMOS and PCB level)

Matthias Ludwig, Vincent Krämer 2024-03-20



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Introduction





Secured hardware is vital for system-critical applications



Hardware fingerprints claim to enable realizing security goals such as anti-counterfeiting, secured key storage, or authentication



Evaluating the **claimed property** that fingerprints are **protected from being reproduced** by direct physical characterization



Introduction: Fingerprinting

Example: Ring Oscillator

Equally designed and only influenced by randomly occurring manufacturing variances





Background & Research Question

Observing – Side-Channel

"Side-Channel Analysis of 'PUFs' and Fuzzy Extractors"

"Localized electromagnetic analysis of RO 'PUFs'"

[1], [2]

$\widehat{\mathbf{o}}$

Semi-Invasive – Optical

Attacks on 'PUFs' by photonic emission analysis

Identification of fingerprints by correlation optical images and emission fingerprints

[3], [4]



Demonstrated a Focused Ion Beam circuit edit with which they produced a physical clone of their Proof-of-Concept SRAM 'PUF' implementation

[5]





Research question: Can hardware fingerprints be effectively characterized by direct physical measurement methods?



Physical Model

To effectively characterize fingerprints, we need a **link between hardware and response**



Research Agenda







Case Studies



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Recap: Start-Up SRAM Cell





Ground Truth Generation & Evaluation





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Physical Model Generation [7]



Measurement and Data Analysis: Probing (WIP)



- Place nanoprobes on transistors
- **Output:** Voltage transfer characteristics
- Preferred cells is evaluated by equation from [6]
- **Does not scale** for many cells





Measurement: Layout

 Allows to measure length/width of transistors automatically

- Transconductance and, ultimately cell state depend on
 - Oxide thickness
 - Transistor geometry (L/W)
 - Doping parameters

- Only parameters length/width available in layout analysis

$$\beta_i = \frac{1}{2} \cdot \mu_i \cdot \frac{\varepsilon_0 \cdot \varepsilon_{r,ox}}{d_{ox}} \cdot \frac{W}{L}$$







Data Analysis: Layout (WIP)

- Cells are detected by image processing (red)
- Width/length of transistors (green)

Cell	Transistor	L [nm]	W [nm]	Ground truth
	M1	62	116	
$\mathbf{C}0$	M2	60	71	1
CO	M3	58	63	1
	M4	61	116	
	M 1	61	119	
C1	M2	58	68	0
CI	M 3	58	66	0
	M 4	64	114	

- Find correlation between measurements and ground truth
- Preferred cells is evaluated by formula [7]



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Overview



Physical Model Generation







Resistance Measurement: Electrical

Method	Resolution	Cost
Laboratory set-up (resistance) (Keithley Model 4200, KS PM8, 407B simac tips)	0.1μΩ, -	~100 000€
	$\begin{array}{c} \cdot 10^{-2} \\ 6 \\ 4 \\ 2 \\ 0 \\ 0 \\ 0.1 \end{array}$	PCB 1 PCB 2 PCB 3

Fig. 14: Electrical resistance measurement results.

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Resistance Measurement: Optical









Fig. 14: Electrical resistance measurement results.



Both the **electrical** and the **optical** measurement **correlate** with the manufacturer values

Fig. 15: Geometrical max width measurement results.



Results of Capacitance Measurement: Electrical

Method	Resolution	Cost
Laboratory set-up (capacitance) (Andeen Hagerling 2700A, KS PM8, HM 7044, 407B simac tips)	-, 0.1 nF	~80000€





The measurement **correlates** with the manufacturer values

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Conclusion





We propose a methodology to transfer hardware physics and responses into a physical model



Evaluation capability of hardware primitives' correlates to financial expenditure



Hardware design of fingerprints must take **reverse engineering / physical inspection** capabilities into account





Literature

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[6] Cortez, Mafalda / Dargar, Apurva / Hamdioui, Said / Schrijen, Geert-Jan; **Modeling SRAM start-up behavior for Physical Unclonable Functions**; 2012 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT); IEEE



Reasons for Manufacturing Variations

- Variations in Si0_2 Thickness
- Alignment of mask
- Variations in exposure / angle
- Variations due to distribution of etch liquid
- Variations in diffusion

- \rightarrow Process Parameters affected by Variations (Drennan et al. 2003):
- Electron / Hole Mobility $\mu n / \mu p$
- Flatband Voltage Vfb
- Substrate dopant concentration Nsub
- Gate oxide thickness tOx
- Length offset ΔL , Width offset ΔW , Short channel effect, Narrow width effect
- Source/drain sheet resistance



On-board measurement

- Evaluate the difference by operational amplifiers
- First differential amplifiers:
 - Put the voltage over R1/R2 to an single-ended output
- Second differential amplifier:
 - Amplify the difference to positive / negative value
- Gain is determined by R5/R3 (if R3=R4 and R5=R6)





On-board measurement

- Evaluate the difference by a schering bridge
- Difference of capacitance defines current flow through R1 resistor
- Operational amplifier increases this voltage
- Xor gate checks if signals are in phase
 - Produce stable 0/1 output

